

<b>Notice of References Cited</b>	Application/Control No. 09/823,410	Applicant(s)/Patent Under Reexamination CHIN, HON WAH	
	Examiner YOUNG T. TSE	Art Unit 2637	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,888,763 A	12-1989	Hatfield et al.	370/445
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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